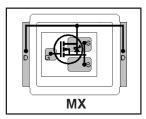
# International Rectifier

## IRF6715MPbF IRF6715MTRPbF

DirectFET™ Power MOSFET ②

- RoHs Compliant and Halogen Free ①
- Low Profile (<0.6 mm)
- Dual Sided Cooling Compatible ①
- Ultra Low Package Inductance
- Optimized for High Frequency Switching ①
- Ideal for CPU Core DC-DC Converters
- Optimized for Sync. FET socket of Sync. Buck Converter ①
- Low Conduction and Switching Losses
- Compatible with existing Surface Mount Techniques ①
- 100% Rg tested

1	Typical values (unless otherwise specified)							
	$V_{DSS}$	V	GS		R <sub>DS(on)</sub>	R	R <sub>DS(on)</sub>	
	25V ma	x ±20\	/ max	1.3	m $\Omega$ @ 10 $^\circ$		Ω@ 4.5V	
	Q <sub>g tot</sub>	$\mathbf{Q}_{gd}$	Q	gs2	Q <sub>rr</sub>	Q <sub>oss</sub>	V <sub>gs(th)</sub>	
	40nC	12.0nC	5.3	3nC	37nC	26nC	1.9V	





Applicable DirectFET Outline and Substrate Outline (see p.7,8 for details) ①

SQ SX ST MQ MX	MT	MP		
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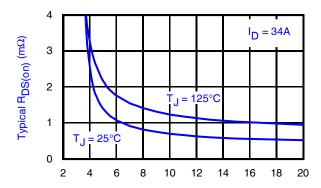
#### **Description**

The IRF6715MPbF combines the latest HEXFET® Power MOSFET Silicon technology with the advanced DirectFET™ packaging to achieve the lowest on-state resistance in a package that has the footprint of a SO-8 and only 0.6 mm profile. The DirectFET package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques, when application note AN-1035 is followed regarding the manufacturing methods and processes. The DirectFET package allows dual sided cooling to maximize thermal transfer in power systems, improving previous best thermal resistance by 80%.

The IRF6715MPbF balances both low resistance and low charge along with ultra low package inductance to reduce both conduction and switching losses. The reduced total losses make this product ideal for high efficiency DC-DC converters that power the latest generation of processors operating at higher frequencies. The IRF6715MPbF has been optimized for parameters that are critical in synchronous buck including Rds(on), gate charge and Cdv/dt-induced turn on immunity. The IRF6715MPbF offers particularly low Rds(on) and high Cdv/dt immunity for synchronous FET applications.

**Absolute Maximum Ratings** 

	Parameter	Max.	Units
$V_{DS}$	Drain-to-Source Voltage	25	V
$V_{GS}$	Gate-to-Source Voltage	±20	V
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ③	34	
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ③	27	_
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ④	180	A
I <sub>DM</sub>	Pulsed Drain Current ®	270	
E <sub>AS</sub>	Single Pulse Avalanche Energy ®	200	mJ
I <sub>AR</sub>	Avalanche Current ©	27	Α



V<sub>GS,</sub> Gate -to -Source Voltage (V)

Fig 1. Typical On-Resistance Vs. Gate Voltage

#### Notes:

- ① Click on this section to link to the appropriate technical paper.
- ② Click on this section to link to the DirectFET Website.
- 3 Surface mounted on 1 in. square Cu board, steady state.

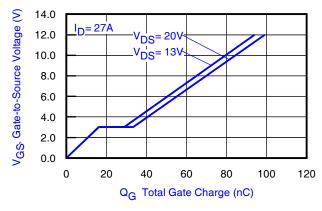


Fig 2. Typical Total Gate Charge vs Gate-to-Source Voltage

- (4) T<sub>C</sub> measured with thermocouple mounted to top (Drain) of part.
- S Repetitive rating; pulse width limited by max. junction temperature.
- © Starting  $T_J = 25$ °C, L = 0.56mH,  $R_G = 25Ω$ ,  $I_{AS} = 27$ A.

## Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	25			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		17		mV/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		1.3	1.6	mΩ	$V_{GS} = 10V, I_D = 34A$ ⑦
			2.1	2.7		$V_{GS} = 4.5V, I_{D} = 27A$ ⑦
$V_{GS(th)}$	Gate Threshold Voltage	1.4	1.9	2.4	V	$V_{DS} = V_{GS}, I_{D} = 100 \mu A$
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Coefficient		-6.2		mV/°C	$\mathbf{v}_{\mathrm{DS}} = \mathbf{v}_{\mathrm{GS}}, \mathbf{v}_{\mathrm{D}} = \mathbf{v}_{\mathrm{ODA}}$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			1.0	μA	$V_{DS} = 20V, V_{GS} = 0V$
				150		$V_{DS} = 20V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage			-100		V <sub>GS</sub> = -20V
gfs	Forward Transconductance	135			S	$V_{DS} = 13V, I_{D} = 27A$
$Q_g$	Total Gate Charge		40	59		
Q <sub>gs1</sub>	Pre-Vth Gate-to-Source Charge		12			$V_{DS} = 13V$
Q <sub>gs2</sub>	Post-Vth Gate-to-Source Charge		5.3		nC	$V_{GS} = 4.5V$
$Q_gd$	Gate-to-Drain Charge		12			I <sub>D</sub> = 27A
Q <sub>godr</sub>	Gate Charge Overdrive		11			See Fig. 15
Q <sub>sw</sub>	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )		17			
Q <sub>oss</sub>	Output Charge		26		nC	$V_{DS} = 16V, V_{GS} = 0V$
$R_G$	Gate Resistance		1.1	2.0	Ω	
t <sub>d(on)</sub>	Turn-On Delay Time		20			$V_{DD} = 13V, V_{GS} = 4.5V$ ⑦
t <sub>r</sub>	Rise Time		31		ns	I <sub>D</sub> = 27A
t <sub>d(off)</sub>	Turn-Off Delay Time		16		İ	$R_G = 1.8\Omega$
t <sub>f</sub>	Fall Time		12		İ	See Fig. 17
C <sub>iss</sub>	Input Capacitance		5340			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		1280		pF	$V_{DS} = 13V$
C <sub>rss</sub>	Reverse Transfer Capacitance		600			f = 1.0MHz

## **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions		
Is	Continuous Source Current			00		MOSFET symbol		
	(Body Diode)		<u> </u>		Α	showing the		
I <sub>SM</sub>	Pulsed Source Current		270		070	070	_ ^	integral reverse
	(Body Diode) ⑤			270		p-n junction diode.		
$V_{SD}$	Diode Forward Voltage			1.0	٧	$T_J = 25^{\circ}C$ , $I_S = 27A$ , $V_{GS} = 0V$ ⑦		
t <sub>rr</sub>	Reverse Recovery Time		28	42	ns	$T_J = 25^{\circ}C, I_F = 27A$		
$Q_{rr}$	Reverse Recovery Charge		37	56	nC	di/dt = 200A/µs ⑦		

### Notes:

 $\ensuremath{ \bigcirc }$  Pulse width  $\le 400 \mu s;$  duty cycle  $\le 2\%$ 

**Absolute Maximum Ratings** 

	Parameter	Max.	Units
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation ③	2.8	
P <sub>D</sub> @T <sub>A</sub> = 70°C	Power Dissipation ③	1.8	W
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation ④	78	
T <sub>P</sub>	Peak Soldering Temperature	270	
TJ	Operating Junction and	-40 to + 150	°C
T <sub>STG</sub>	Storage Temperature Range		

### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JA}$	Junction-to-Ambient 3®		45	
$R_{\theta JA}$	Junction-to-Ambient ®®	12.5		
$R_{\theta JA}$	Junction-to-Ambient 9®	20		°C/W
$R_{\theta JC}$	Junction-to-Case 40		<del></del> 1.6	
$R_{\theta J\text{-PCB}}$	Junction-to-PCB Mounted	1.0		
	Linear Derating Factor ③	0.0	0.022	

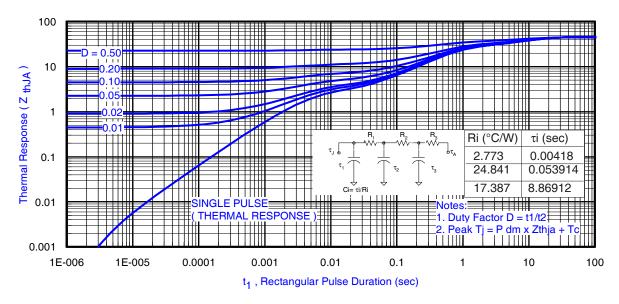
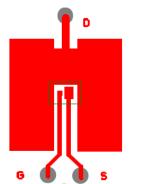


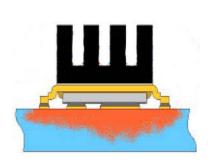
Fig 3. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient 3

#### Notes:

- $\ensuremath{\$}$  Used double sided cooling , mounting pad with large heatsink.
- Mounted on minimum footprint full size board with metalized back and with small clip heatsink.
- ${}^{\circledR}$   $R_{\theta}$  is measured at  $T_J$  of approximately  $90^{\circ}C$  .



③ Surface mounted on 1 in. square Cu (still air).



 Mounted to a PCB with small clip heatsink (still air)



 Mounted on minimum footprint full size board with metalized back and with small clip heatsink (still air)

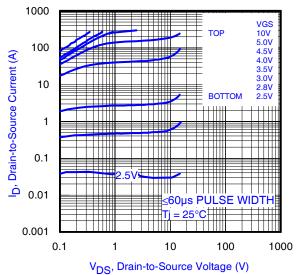
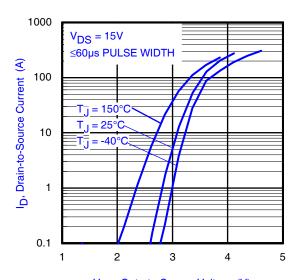


Fig 4. Typical Output Characteristics



V<sub>GS</sub>, Gate-to-Source Voltage (V) **Fig 6.** Typical Transfer Characteristics

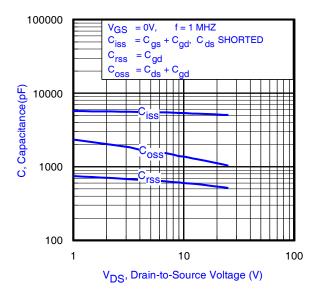


Fig 8. Typical Capacitance vs.Drain-to-Source Voltage

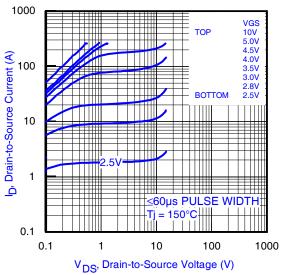


Fig 5. Typical Output Characteristics

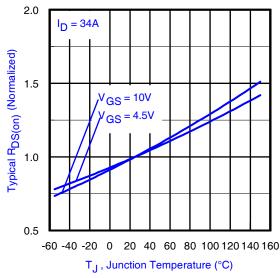


Fig 7. Normalized On-Resistance vs. Temperature

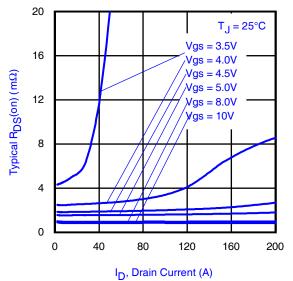


Fig 9. Typical On-Resistance Vs. Drain Current and Gate Voltage

4

### International

## IRF6715MPbF

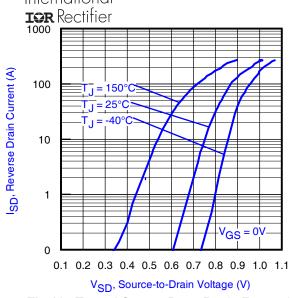


Fig 10. Typical Source-Drain Diode Forward Voltage

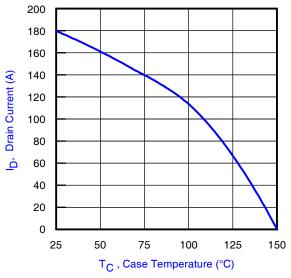


Fig 12. Maximum Drain Current vs. Case Temperature

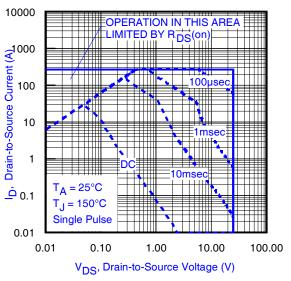
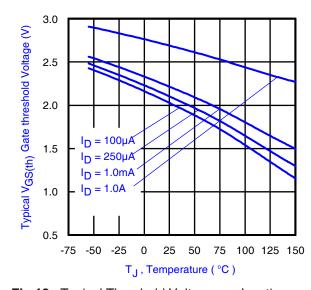


Fig11. Maximum Safe Operating Area



**Fig 13.** Typical Threshold Voltage vs. Junction Temperature

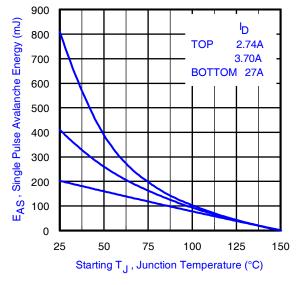


Fig 14. Maximum Avalanche Energy vs. Drain Current

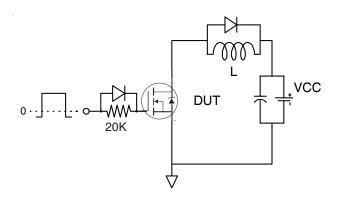


Fig 15a. Gate Charge Test Circuit

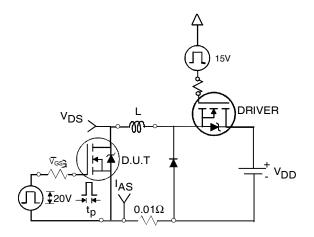


Fig 16a. Unclamped Inductive Test Circuit

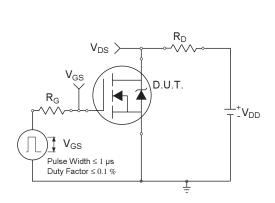


Fig 17a. Switching Time Test Circuit

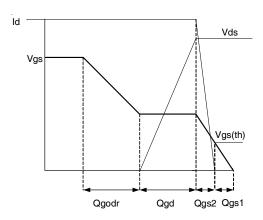


Fig 15b. Gate Charge Waveform

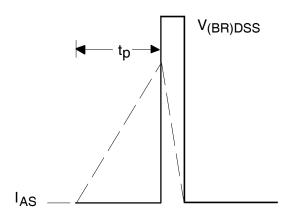


Fig 16b. Unclamped Inductive Waveforms

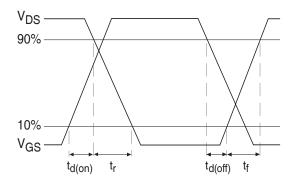


Fig 17b. Switching Time Waveforms

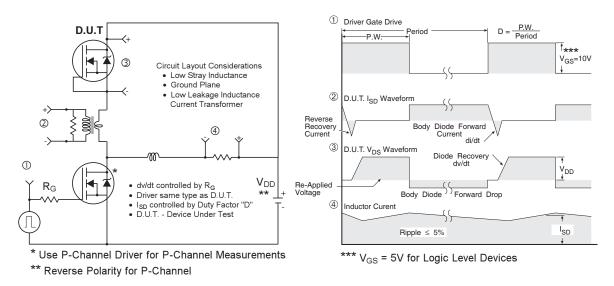
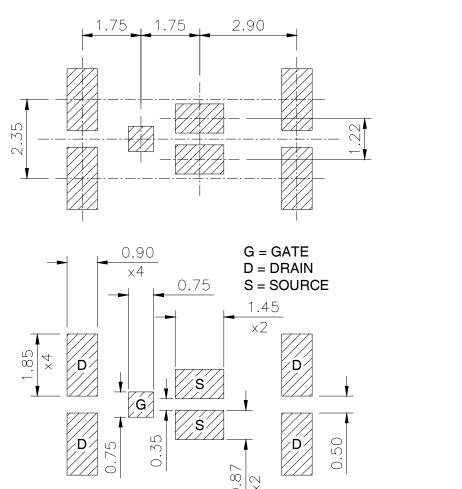


Fig 18. Diode Reverse Recovery Test Circuit for HEXFET® Power MOSFETs

## DirectFET™ Board Footprint, MX Outline (Medium Size Can, X-Designation).

Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET.

This includes all recommendations for stencil and substrate designs.

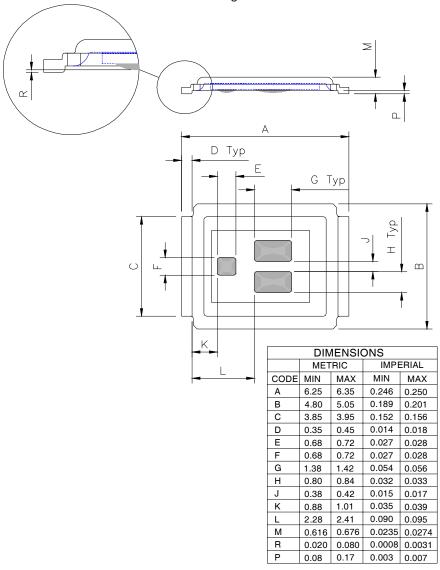


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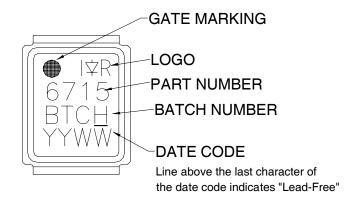
## IRF6715MPbF

## DirectFET™ Outline Dimension, MX Outline (Medium Size Can, X-Designation).

Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET. This includes all recommendations for stencil and substrate designs.

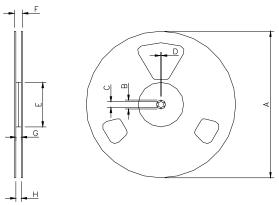


## DirectFET™ Part Marking



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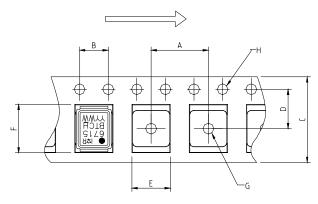
## DirectFET™ Tape & Reel Dimension (Showing component orientation).



NOTE: Controlling dimensions in mm Std reel quantity is 4800 parts. (ordered as IRF6715MTRPBF). For 1000 parts on 7" reel, order IRF6715MTR1PBF

REEL DIMENSIONS									
S.	TANDARI	OPTION	I (QTY 48	TR1 OPTION (QTY 1000)					
	ME	TRIC	IMP	ERIAL	METRIC		IMPERIAL		
CODE	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
Α	330.0	N.C	12.992	N.C	177.77	N.C	6.9	N.C	
В	20.2	N.C	0.795	N.C	19.06	N.C	0.75	N.C	
С	12.8	13.2	0.504	0.520	13.5	12.8	0.53	0.50	
D	1.5	N.C	0.059	N.C	1.5	N.C	0.059	N.C	
Е	100.0	N.C	3.937	N.C	58.72	N.C	2.31	N.C	
F	N.C	18.4	N.C	0.724	N.C	13.50	N.C	0.53	
G	12.4	14.4	0.488	0.567	11.9	12.01	0.47	N.C	
Н	11.9	15.4	0.469	0.606	11.9	12.01	0.47	N.C	

#### LOADED TAPE FEED DIRECTION



NOTE: CONTROLLING DIMENSIONS IN MM

DIMENSIONS								
	ME	TRIC	IMPERIAL					
CODE	MIN	MAX	MIN	MAX				
Α	7.90	8.10	0.311	0.319				
В	3.90	4.10	0.154	0.161				
С	11.90	12.30	0.469	0.484				
D	5.45	5.55	0.215	0.219				
E	5.10	5.30	0.201	0.209				
F	6.50	6.70	0.256	0.264				
G	1.50	N.C	0.059	N.C				
Н	1.50	1.60	0.059	0.063				

Data and specifications subject to change without notice. This product has been designed and qualified for the Consumer market.

Qualification Standards can be found on IR's Web site.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

TAC Fax: (310) 252-7903

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